Application/Control No.	Applicant(s)/Patent under Reexamination	
09/922,178	LEWIS, CRAIG	
Examiner	Art Unit	
Minh Dieu Nguyen	2137	

SEARCHED						
Class	Subclass	Date	Examiner			
713	184	8/22/2006	MDN			
726	2,6,18	8/22/2006	MDN			
			1			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
	<u> </u>					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated inventor name search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	8/22/2006	MDN		
Updated text and class search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	8/22/2006	MDN		
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